

| | | | | |
|-----------------------------------|--|-------------------------|---|--|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/532,256 | REGNARD ET AL. | |
| Examiner | | Art Unit | | |
| Ondria Garner | | 2834 | Page 1 of 2 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| * | A | US-4,518,886 A | 05-1985 | Kaneyuki, Kazutoshi | 310/71 |
| * | B | US-5,006,742 A | 04-1991 | Strobl et al. | 310/88 |
| * | C | US-2001/0054853 A1 | 12-2001 | Hayashi et al. | 310/71 |
| * | D | US-2002/0158523 A1 | 10-2002 | Abadia et al. | 310/68.00B |
| * | E | US-6,509,652 B2 | 01-2003 | Yumita, Yukinobu | 290/54 |
| * | F | US-2004/0051404 A1 | 03-2004 | Kurosawa et al. | 310/049.00R |
| * | G | US-2005/0023912 A1 | 02-2005 | Lin et al. | 310/089 |
| * | H | US-2005/0073204 A1 | 04-2005 | Puterbaugh et al. | 310/089 |
| * | I | US-2005/0121988 A1 | 06-2005 | Howe et al. | 310/090 |
| * | J | US-2005/0168082 A1 | 08-2005 | Kondo et al. | 310/068.00D |
| * | K | US-7,005,767 B2 | 02-2006 | Oh et al. | 310/89 |
| * | L | US-2006/0043805 A1 | 03-2006 | Bradfield, Michael D. | 310/068.00D |
| * | M | US-2006/0119197 A1 | 06-2006 | Puterbaugh et al. | 310/087 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|-----------------|-----------------|----------------|
| * | N | DE 19605757 A1 | 08-1996 | Germany | ABADIA et al. | H02K 05/22 |
| * | O | FR 2730875 A1 | 08-1996 | France | ABADIA et al. | H02K 05/04 |
| * | P | FR 2783648 A1 | 03-2000 | France | BLANCHET et al. | H02K 05/22 |
| * | Q | EP 1024582 A2 | 08-2000 | European Patent | YUI et al. | H02K 05/04 |
| * | R | JP 2002017067 A | 01-2002 | Japan | ISHIDA, HIROSHI | H02K 05/22 |
| * | S | JP 2002315397 A | 10-2002 | Japan | ISHIDA et al. | H02P 09/14 |
| * | T | JP 2005033985 A | 02-2005 | Japan | ISHIDA et al. | H02K 11/00 |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

| | | | | |
|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination REGNARD ET AL. | |
| | | 10/532,256 | Examiner Ondria Garner | |
| | | | Art Unit 2834 | Page 2 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-6,034,464 A | 03-2000 | Asao, Yoshihito | 310/263 |
| * | B | US-2004/0256928 A1 | 12-2004 | Kondo et al. | 310/068.00D |
| | C | US- | | | |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| * | N | JP 60245448 A | 12-1985 | Japan | ISHIDA, TAKAO | H02K 11/00 |
| * | O | JP 05176505 A | 07-1993 | Japan | KAWANO et al. | H02K 19/36 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.